

**METHODS AND SYSTEMS FOR DIGITAL TESTING
ON AUTOMATIC TEST EQUIPMENT (ATE)**

ABSTRACT

[027] Methods and systems for digital testing of semiconductor devices are disclosed. The inventions include testing modules (10) for use with automatic test equipment (ATE) 20 and device interface boards (32) in order to extend their capabilities to perform digital testing of semiconductor devices (18). Testing modules (10) disclosed include memory (12) and a test engine (14), which may be configured for digital testing according to further steps of the invention.